

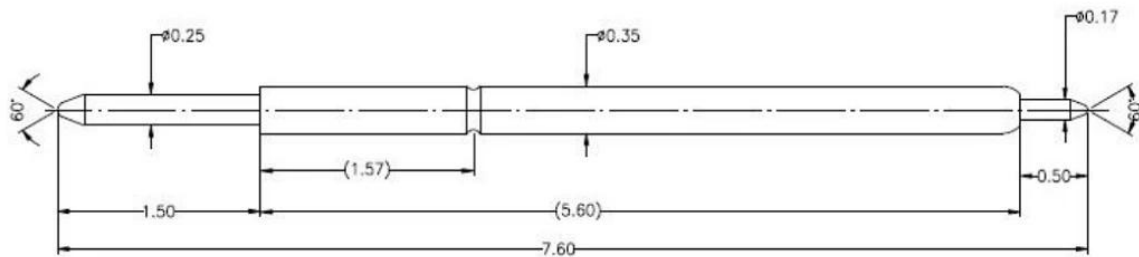
BGA 000 0 000 000 000 0

00:

00	SFENG 00
00 00	00 00 0 SF035B760B30
000	00
0	PhBz
0	SWP
00	0 00 00 00
0 0	30g ± 20 % @ 00 0.65mm 00 0000
00 00	0 50m 0
00 00	1A
MOQ	100PCS 00 00 00 00
00 00	2 ~ 15 0 0 00 000 00

00 00 00:





Probe Specifications (探针各项参数)	Pitch (中心距)	Pointing Accuracy (垂直度/角度)	Cycle Time (循环寿命)	Contact Resistance (接触电阻)	Current Rating-Continuous Time (额定电流-持续时间)	Operating Temperature (使用温度)	Bandwidth (频宽)
/	/	±0.05mm	>80,000次	120mohm max	/	-40~80℃	N/A

Name (名称)		Spring Probe				SF035B760B30		
Initial Travel (初始行程)	Travel(mm) (行程)	Spring Force (弹力)	Part (零件)	Material (材质)	Finish (表面处理)	Size	A4	Design
recommended Travel (推荐行程)	0.65	30	Spring (弹簧)	Music Wire	Gold Plated	Scale	6:1	Check
Full Travel (全行程)	0.8	/	Barrel (针管)	Phosphor Copper	Gold Plated	Unit	mm	Approve
			Left Plunger (左针头)	Becu	Gold Plated	Rev	A0	
			Right Plunger (右针头)	Becu	Gold Plated	Rev	A0	
						Sheet	1/1	
胜峰科技 SFENG PROBE								

□□□ □□ :

- 1.we have 30 years experience in probe pin and have ourself factory.
- 2.we provide free sample and have a testing department.
- 3.we could manufacture products as your request.
- 4.we guarantee best price and good service.

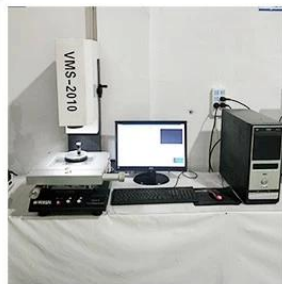
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Spring loaded pin (single) for PCB, ICT, FCT testing etc;
Pogo pin (connector) to establish connection between two printed circuit boards for charging, locating, Battery, Semiconductor & Interconnect applications;
Double ended probe for BGA and Semiconductor testing;
Universal pin without spring, coating pin, LM pin with QZ and VZ series;
High current probe, Switch probe, Capacitance needle;
Terminal & receptacle /socket;
Other related electronic components, 30# OK wire, Jig locks, POM, Iron hinge etc

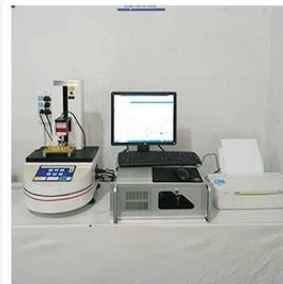
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1. Agilent current testing



2. Quadratic element



3. Load Curve Meter



4. Bond Test



5. Life Fatigue Test



6. Microscope

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Standard products will be delivered out within 3 days. Customized products will be sent out within 15 days.

